


<b>Search Notes</b>  	<b>Application/Control No.</b>  09717303	<b>Applicant(s)/Patent Under Reexamination</b>  WANG BALDONADO ET AL.
	<b>Examiner</b>  DJENANE M BAYARD	<b>Art Unit</b>  2444

SEARCHED			
Class	Subclass	Date	Examiner
709	203, 204, 206, 207	4/5/11	db

SEARCH NOTES		
Search Notes	Date	Examiner
East	4/5/11	db
Double Patenting Search	4/5/11	db
NPL (Google Scholar)	4/5/11	db

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	203, 204, 206, 207	4/5/11	db

	/D. M. B./ Primary Examiner.Art Unit 2444
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